

Notice of References Cited	Application/Control No. 10/022,284	Applicant(s)/Patent Under Reexamination TOMIHARA ET AL.	
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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
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FOREIGN PATENT DOCUMENTS

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	N	JP 10-241724	09-1998	Japan	Hirakawa et al.	H01M 10/28
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